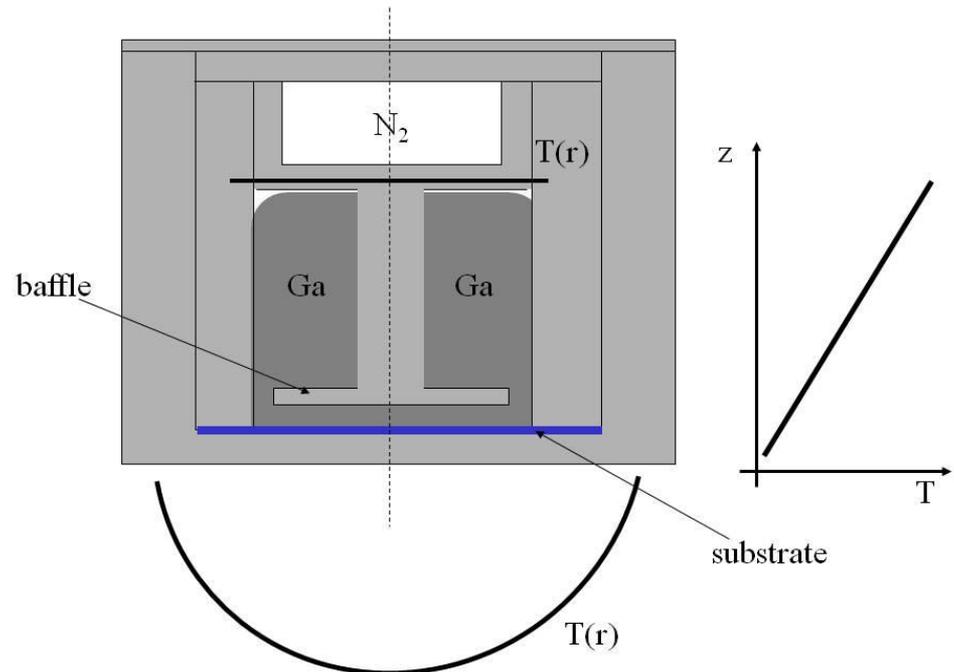


# High Nitrogen Pressure Solution (HNPS) growth method

## Seeded Growth LPE Growth – Single Seed Configuration

The deposition of GaN takes place on a substrate, in order to force the growth in a particular direction. Few kinds of substrates, i.e.: HNPS-GaN, HVPE-GaN, SiC, sapphire, and sapphire/GaN MOCVD templates, were used.

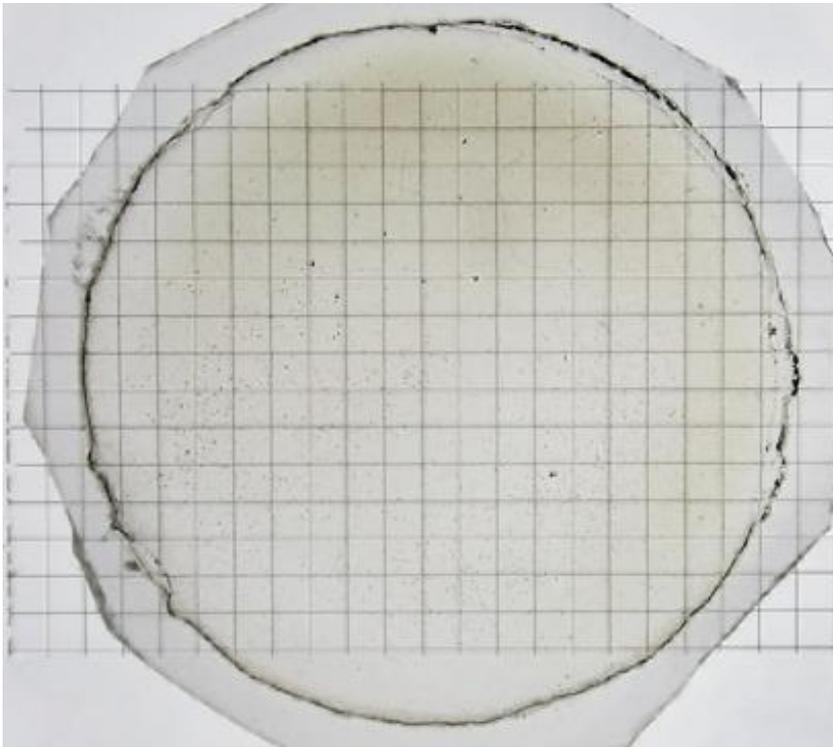
A crucible with a baffle plate positioned close to the seed, axial and radial temperature distributions.



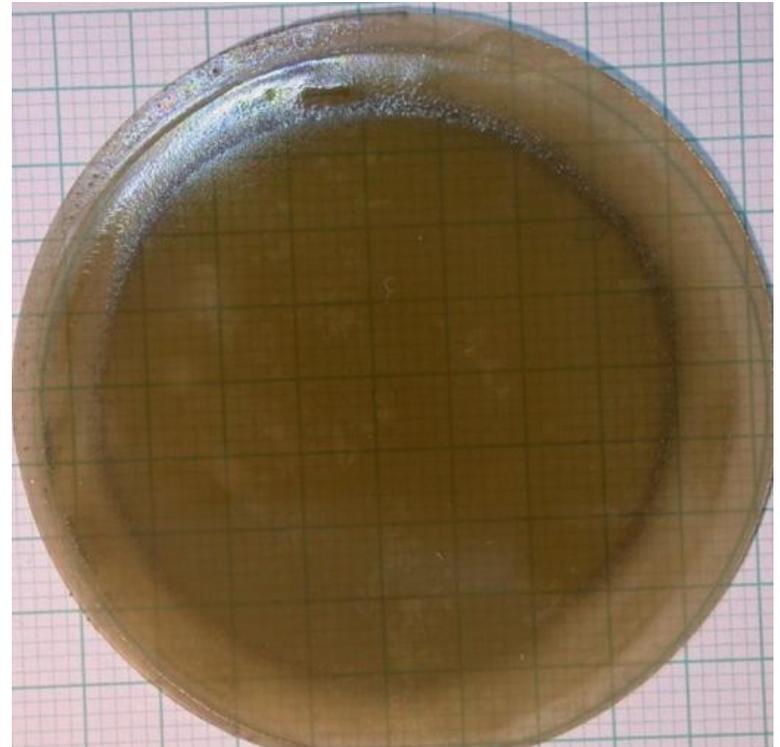
# Seeded Growth

## LPE Growth – Single Seed Configuration

The baffle plate allows to obtain a flat (macroscopically) crystallization front on the substrate and consequently to maintain a flat GaN surface during a long crystallization run.



**GaN grown on a MOCVD-GaN/sapphire template**



**GaN grown on a free standing HVPE-GaN**

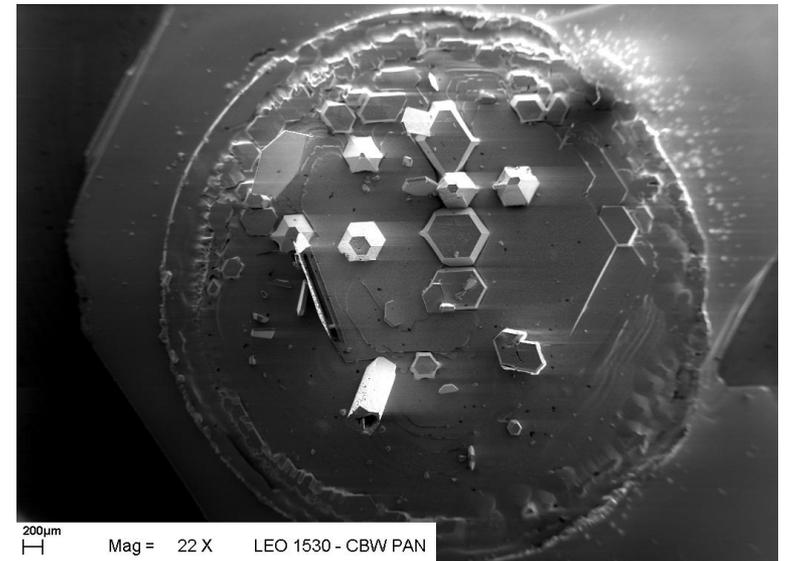
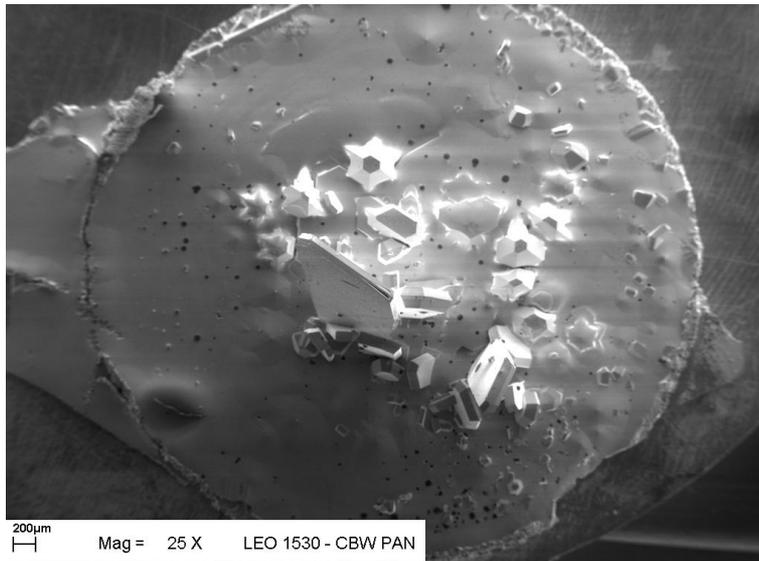
# Seeded Growth

## LPE Growth – Single Seed Configuration

The polarity of the GaN seed's surface is determined and controlled by the Ga solution and its impurities.

The crystallization process is perturbed when the nitrogen polar surface (000-1) of the GaN substrate is exposed to the liquid gallium.

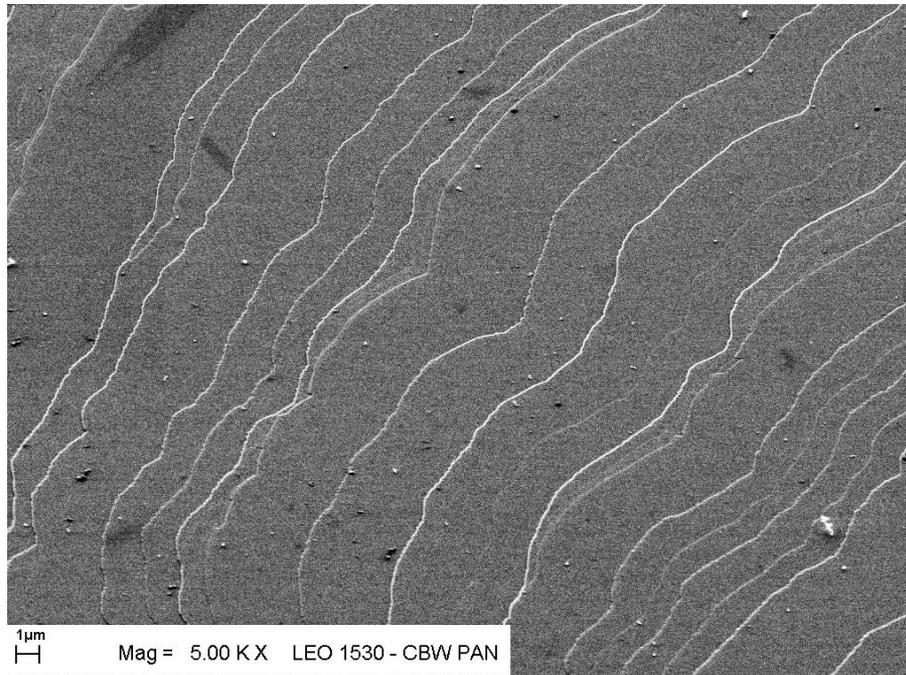
The presence of several growth centers is observed. The simultaneous nucleation and growth of randomly oriented crystals is also noticed.



# Seeded Growth

## LPE Growth – Single Seed Configuration

On the gallium polar surface (0001) the growth mode is macroscopically stable and proceeds by the steps propagation from the center of the sample to its sides. The average growth rate, determined by a comparison of a seed's weight before and after the experiment, is of the order of 1  $\mu\text{m}/\text{h}$ .

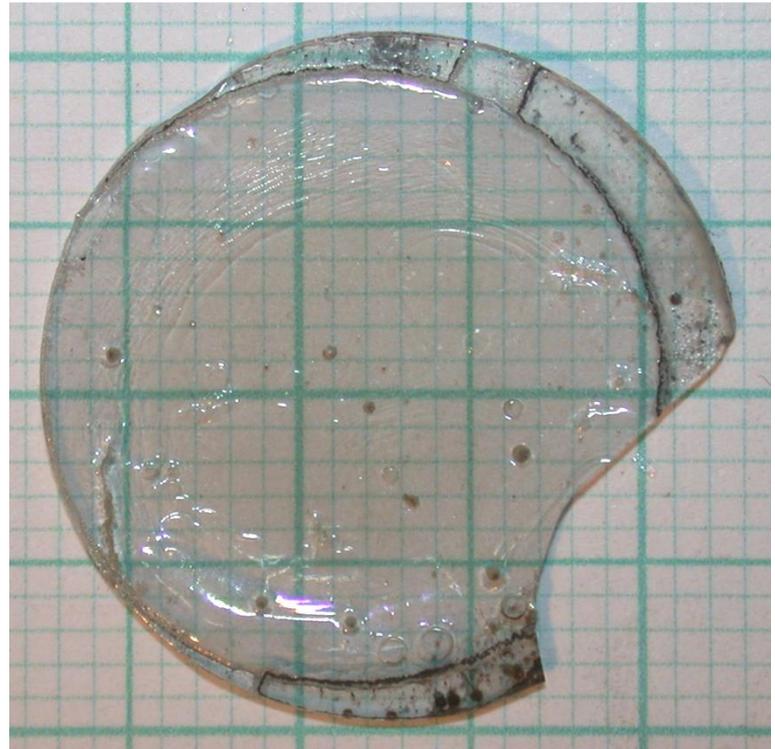
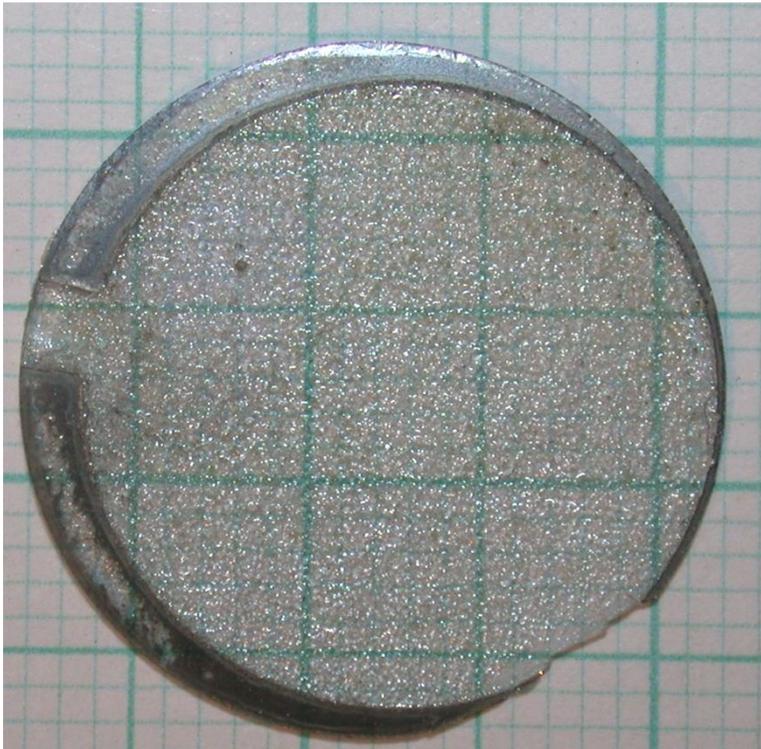


The new deposited material is always n-type with metallic conductivity ( $\sim 5 \times 10^{19} \text{ cm}^{-3}$ ).

# Seeded Growth

## LPE Growth – Single Seed Configuration

For crystallization of highly resistive GaN (in the Ga:Mg solution) the new material is grown by stable way on the (000-1) surface of the seed.



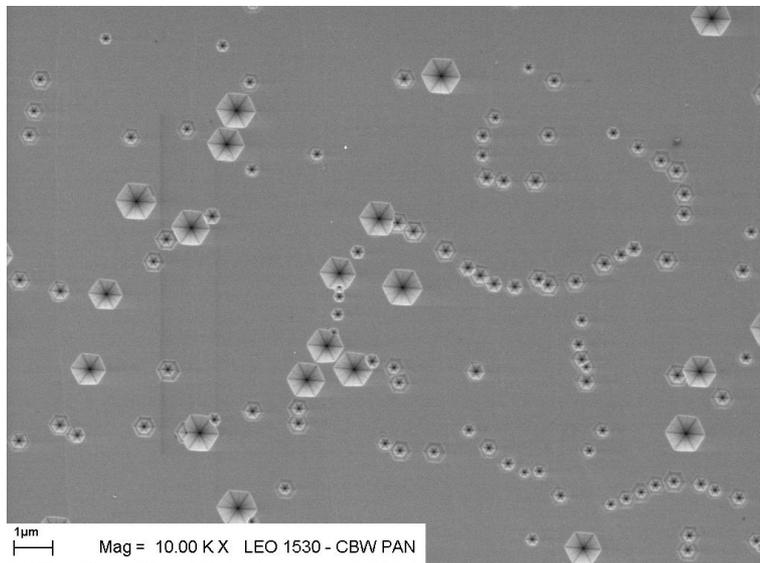
# Seeded Growth

## LPE Growth – Single Seed Configuration

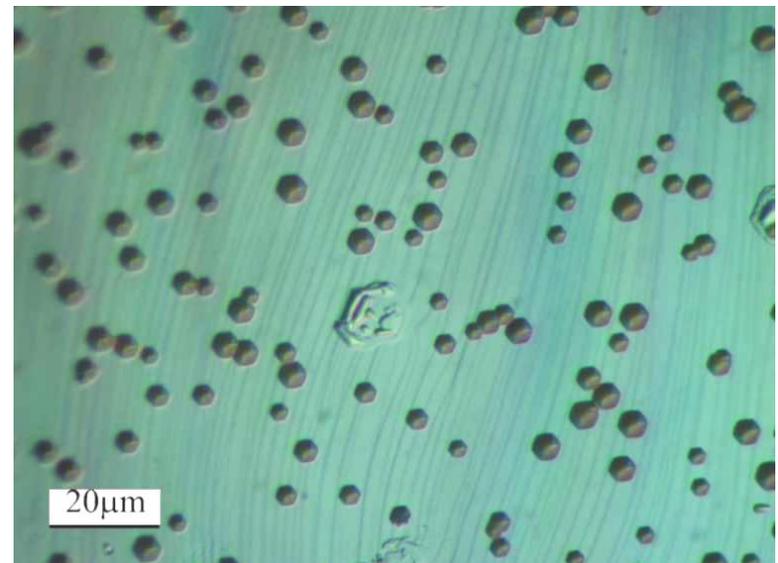
The average dislocation density in GaN crystallized on the HNPS-GaN is always as low as  $10^2 \text{ cm}^{-2}$ .

The dislocation density in the pressure-grown material on sapphire/GaN templates is of the order of  $5 \times 10^7 \text{ cm}^{-2}$ .

Lower defect density can be obtained when HVPE-GaN is used as a substrate. Then, the dislocation density in the starting material is of the order of  $1 \times 10^6 \text{ cm}^{-2}$ .



on a sapphire/GaN template



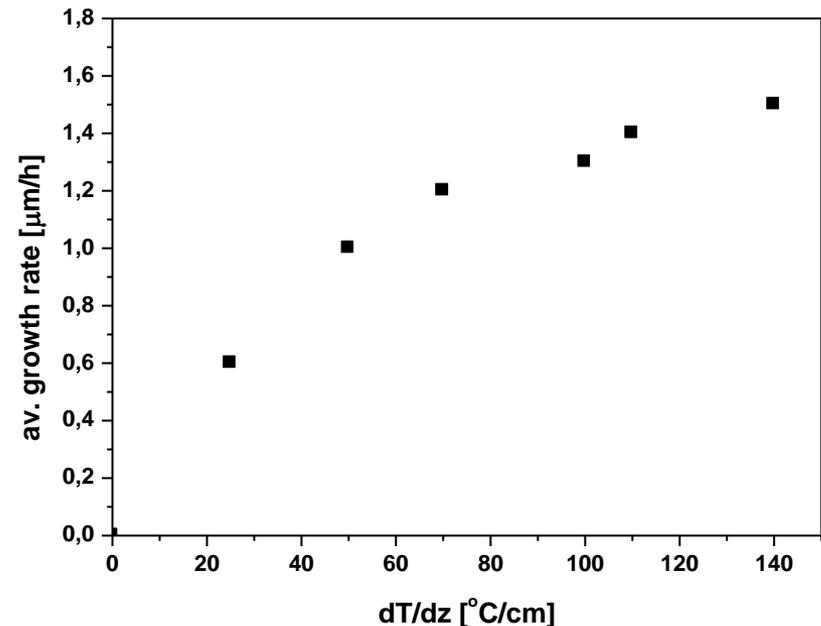
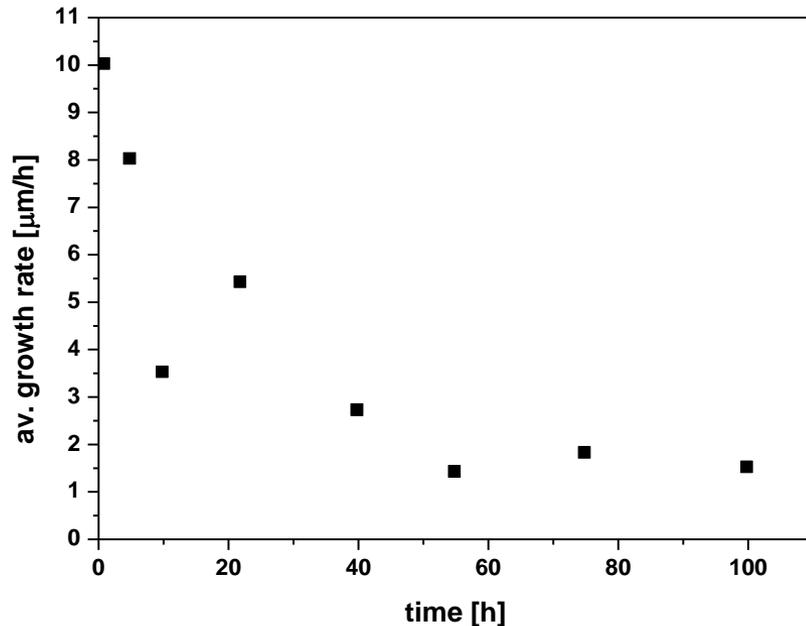
on free standing HVPE-GaN

# Seeded Growth

## LPE Growth – Single Seed Configuration

There are two factors responsible for GaN growth in the c-direction. These factors do not depend on the experimental configurations or the kind of the substrates.

For a short time  $\sim 30$  h. the growth rate is governed mainly by nitrogen transport to the crystallization zone and the observed average growth rate can even attain  $10 \mu\text{m/h}$ . After a longer time  $\sim 100$  h. the surface kinetic factor becomes more important and the average growth rate decreases to  $1 \mu\text{m/h}$ .



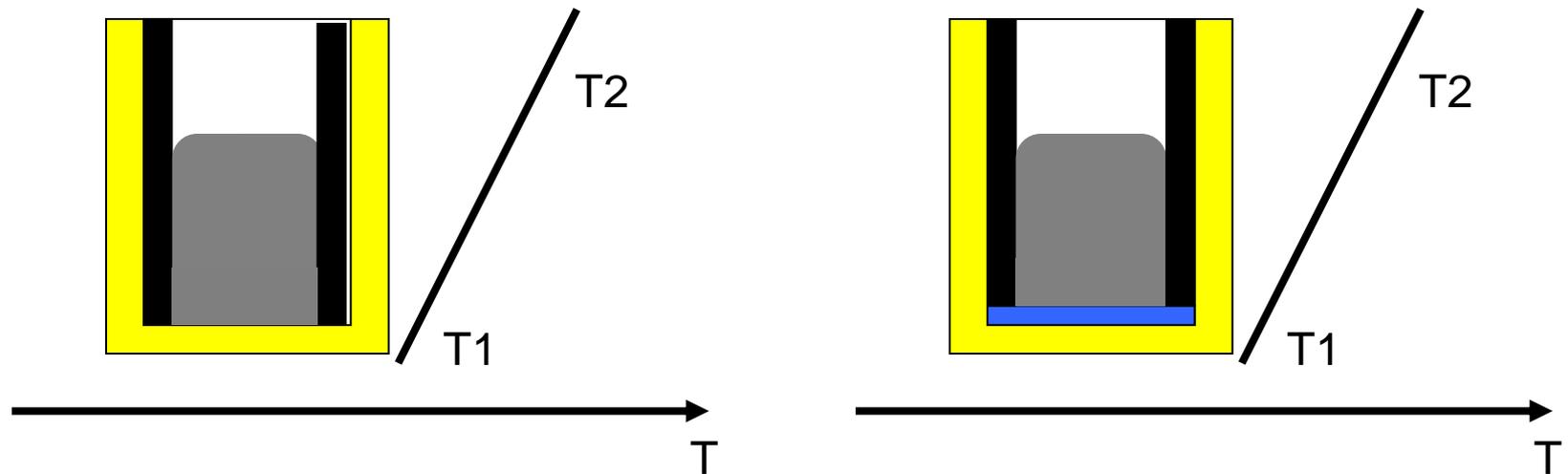
# Seeded Growth

## LPE Growth – Single Seed Configuration

The analysis of GaN mass, crystallized at configuration with and without seed, confirmed that the growth rate on the seed is governed by surface kinetic.

The GaN mass crystallized at the bottom of the crucible without a seed was bigger than the mass crystallized on the seed (with no parasitic growth observed) under the same experimental conditions.

Not all the nitrogen atoms from the solution reaching the seed's surface were adsorbed there.



total GaN mass = mass at the bottom + mass at the wall

$$200 \mu\text{m} = \underline{120} \mu\text{m} + 80 \mu\text{m}$$

$$200 \mu\text{m} = \underline{80} \mu\text{m} + 120 \mu\text{m}$$

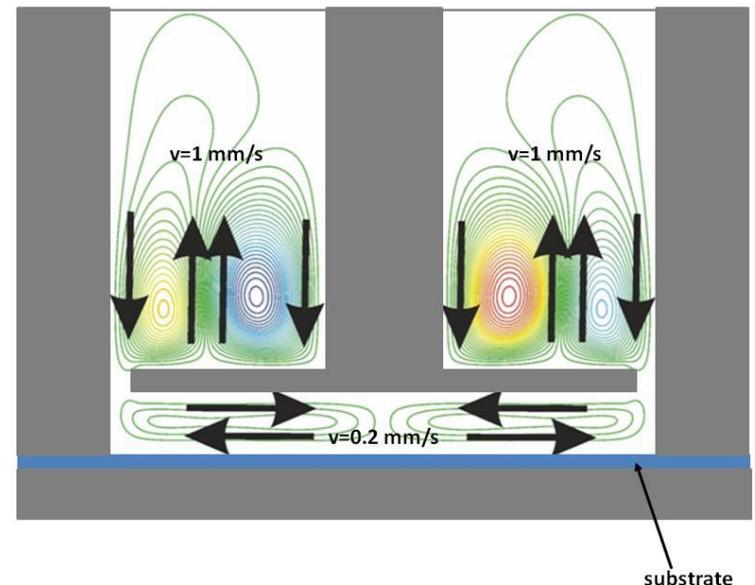
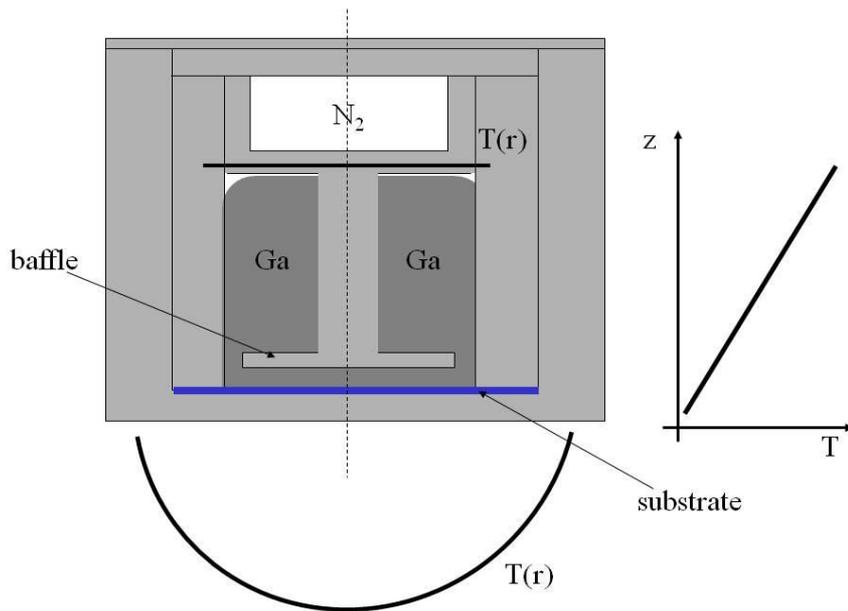
# Seeded Growth

## LPE Growth – Single Seed Configuration

The finite element calculation is used for modeling the convective transport in the solution.

The radial temperature distribution at the bottom of the crucible is approximated as parabolic and the vertical temperature distribution as linear. The radial temperature distribution on the crucible's top is estimated as a constant.

Assuming the laminar flow in the gallium the convective flow velocity in the metal, and the temperature distributions in the liquid, in the seed, and in the crucible wall are determined.



# Seeded Growth

## LPE Growth – Single Seed Configuration

The maximum velocity for the convectational flow above the baffle is of the order of 1mm/s for the used temperature gradients. Under the baffle the convection is very weak. The maximum flow velocities in two rolls reach 0.2 mm/s.

Nitrogen is transported to the baffle by a relatively strong convection. The N atoms are dispersed on the baffle and on the sides (opening areas) they are supplied below the baffle to the seed region. Their velocity is low. By very weak convection process the N atoms are transported to the seed.

Due to a very low convectational flow velocity the growth can be macroscopically stable. The rate, however, is as slow as 1  $\mu\text{m}/\text{h}$ .

